

BLF8G27LS-100

Power LDMOS transistor

Rev. 2 — 5 March 2014

Product data sheet

1. Product profile

1.1 General description

100 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 2500 MHz to 2700 MHz.

Table 1. Typical performance

Typical RF performance at $T_{case} = 25\text{ °C}$ in a common source class-AB production test circuit.

| Test signal | f | I _{DQ} | V _{DS} | P _{L(AV)} | G _p | η _D | ACPR _{5M} |
|------------------|--------------|-----------------|-----------------|--------------------|----------------|----------------|-------------------------|
| | (MHz) | (mA) | (V) | (W) | (dB) | (%) | (dBc) |
| 2-carrier W-CDMA | 2500 to 2700 | 900 | 28 | 25 | 17 | 28 | -32 [1] |

[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF per carrier; 5 MHz carrier spacing.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low thermal resistance providing excellent thermal stability
- Designed for broadband operation (2500 MHz to 2700 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

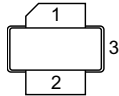
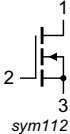
1.3 Applications

- RF power amplifiers for base stations and multi carrier applications in the 2500 MHz to 2700 MHz frequency range



2. Pinning information

Table 2. Pinning

| Pin | Description | Simplified outline | Graphic symbol |
|-----|----------------------------|---|---|
| 1 | drain |  |  sym112 |
| 2 | gate | | |
| 3 | source [1] | | |

[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

| Type number | Package | | |
|---------------|---------|--|---------|
| | Name | Description | Version |
| BLF8G27LS-100 | - | earless flanged ceramic package; 2 leads | SOT502B |

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-----------|----------------------|---------------------|------|------|------|
| V_{DS} | drain-source voltage | | - | 65 | V |
| V_{GS} | gate-source voltage | | -0.5 | +13 | V |
| T_{stg} | storage temperature | | -65 | +150 | °C |
| T_j | junction temperature | [1] | - | 225 | °C |

[1] Continuous use at maximum temperature will affect the reliability, for details refer to the on-line MTF calculator.

5. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Typ | Unit |
|---------------|--|---|-------|------|
| $R_{th(j-c)}$ | thermal resistance from junction to case | $T_{case} = 80\text{ °C}; P_L = 100\text{ W}$ | 0.292 | K/W |

6. Characteristics

Table 6. DC characteristics

$T_j = 25\text{ °C}$ unless otherwise specified.

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---------------|----------------------------------|---|-----|------|-----|---------------|
| $V_{(BR)DSS}$ | drain-source breakdown voltage | $V_{GS} = 0\text{ V}; I_D = 1\text{ mA}$ | 65 | - | - | V |
| $V_{GS(th)}$ | gate-source threshold voltage | $V_{DS} = 10\text{ V}; I_D = 153\text{ mA}$ | 1.5 | 1.9 | 2.3 | V |
| I_{DSS} | drain leakage current | $V_{GS} = 0\text{ V}; V_{DS} = 28\text{ V}$ | - | - | 4.2 | μA |
| I_{DSX} | drain cut-off current | $V_{GS} = V_{GS(th)} + 3.75\text{ V}; V_{DS} = 10\text{ V}$ | - | 29 | - | A |
| I_{GSS} | gate leakage current | $V_{GS} = 11\text{ V}; V_{DS} = 0\text{ V}$ | - | - | 420 | nA |
| g_{fs} | forward transconductance | $V_{DS} = 10\text{ V}; I_D = 153\text{ mA}$ | - | 1.27 | - | S |
| $R_{DS(on)}$ | drain-source on-state resistance | $V_{GS} = V_{GS(th)} + 3.75\text{ V}; I_D = 5.35\text{ A}$ | - | 0.1 | - | Ω |

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA; 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on the CCDF; $f_1 = 2502.5\text{ MHz}; f_2 = 2507.5\text{ MHz}; f_3 = 2692.5\text{ MHz}; f_4 = 2697.5\text{ MHz}$; RF performance at $V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}; T_{case} = 25\text{ °C}$; unless otherwise specified; in a class-AB production test circuit.

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|-------------|--------------------------------------|---------------------------|------|-----|-----|------|
| G_p | power gain | $P_{L(AV)} = 25\text{ W}$ | 15.8 | 17 | - | dB |
| η_D | drain efficiency | $P_{L(AV)} = 25\text{ W}$ | 23 | 28 | - | % |
| RL_{in} | input return loss | $P_{L(AV)} = 25\text{ W}$ | - | -12 | -8 | dB |
| $ACPR_{5M}$ | adjacent channel power ratio (5 MHz) | $P_{L(AV)} = 25\text{ W}$ | - | -32 | -27 | dBc |

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G27LS-100 is capable of withstanding a load mismatch corresponding to $VSWR = 10 : 1$ through all phases under the following conditions: $V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}; P_L = 100\text{ W (CW)}; f = 2500\text{ MHz}$.

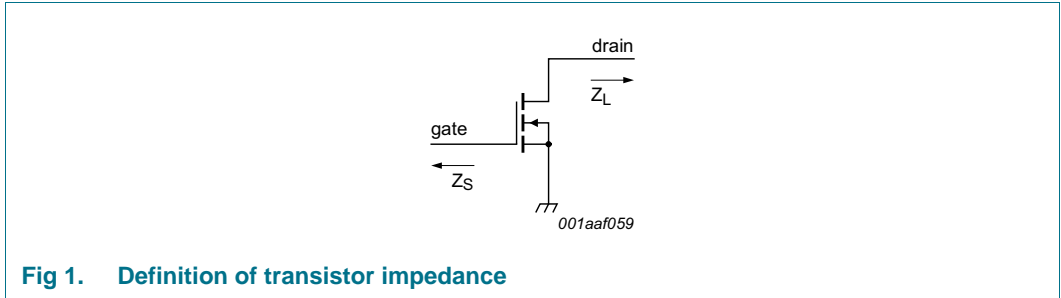
7.2 Impedance information

Table 8. Typical impedance

Measured load-pull data; $V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.

| f (MHz) | Z_S ^[1] (Ω) | Z_L ^[1] (Ω) |
|------------|--------------------------------------|--------------------------------------|
| 2500 | 1.2 - j4.6 | 2.7 - j2.7 |
| 2600 | 2.3 - j5.5 | 2.5 - j2.5 |
| 2700 | 3.8 - j5.2 | 2.1 - j2.6 |

[1] Z_S and Z_L defined in [Figure 1](#).



7.3 Test circuit information

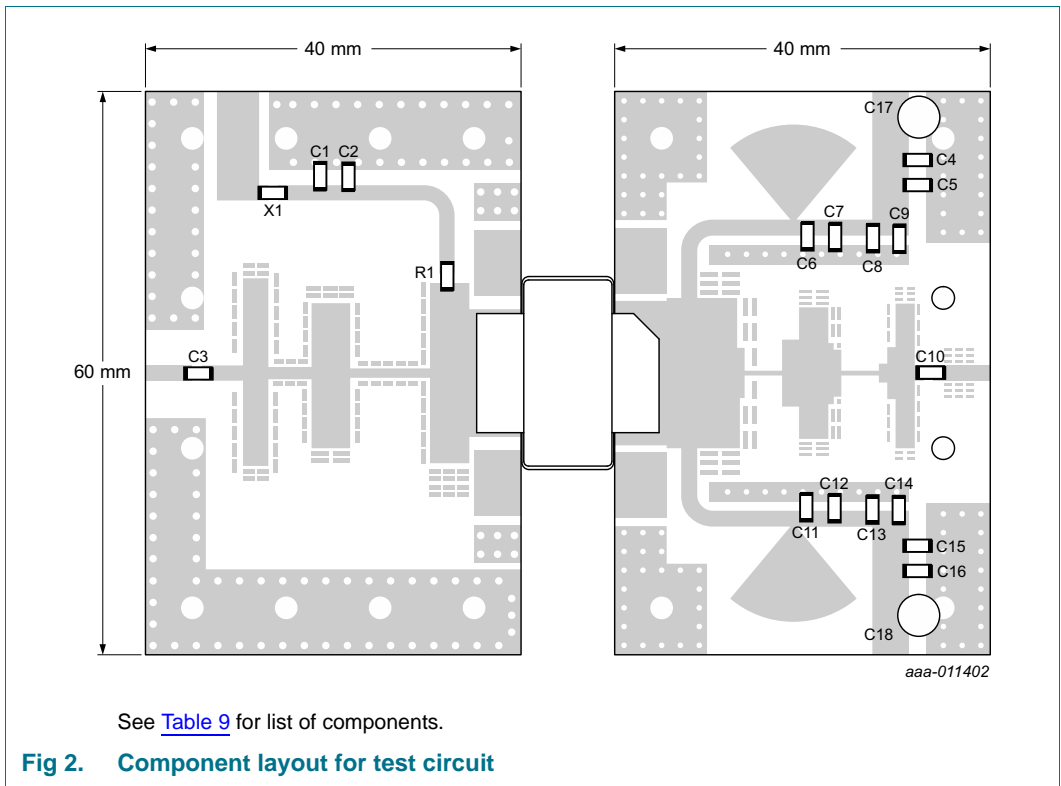


Table 9. List of components

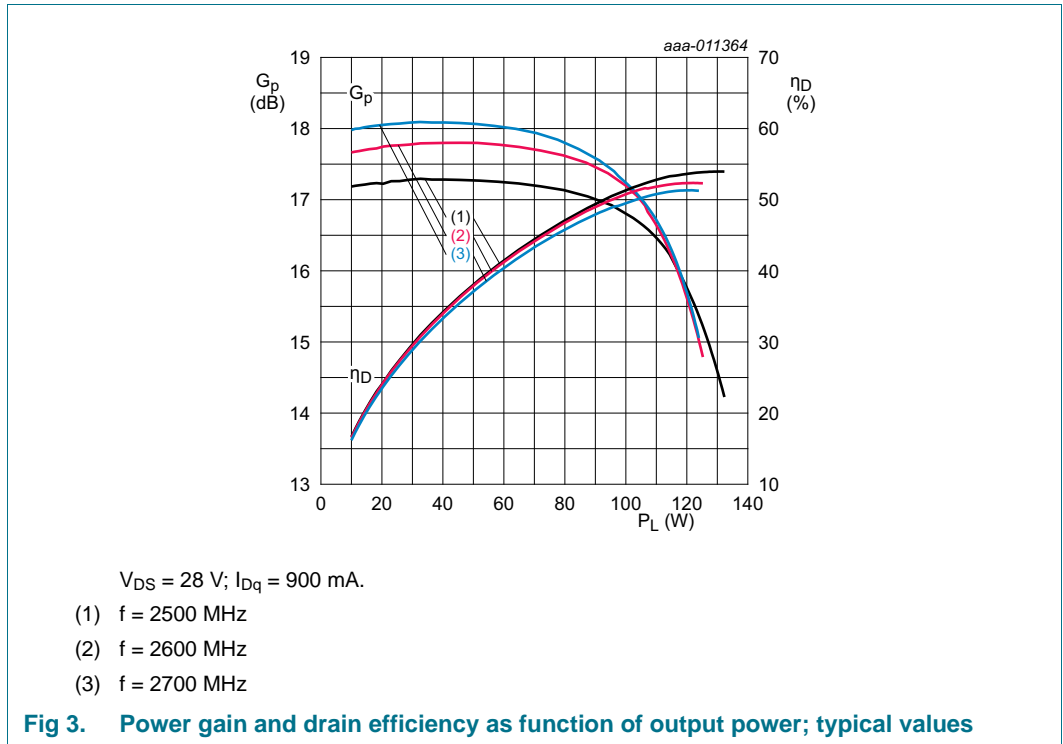
See [Figure 2](#) for component layout.

The used PCB (Printed-Circuit Board) material is Rogers RO4350B with a thickness of 0.762 mm.

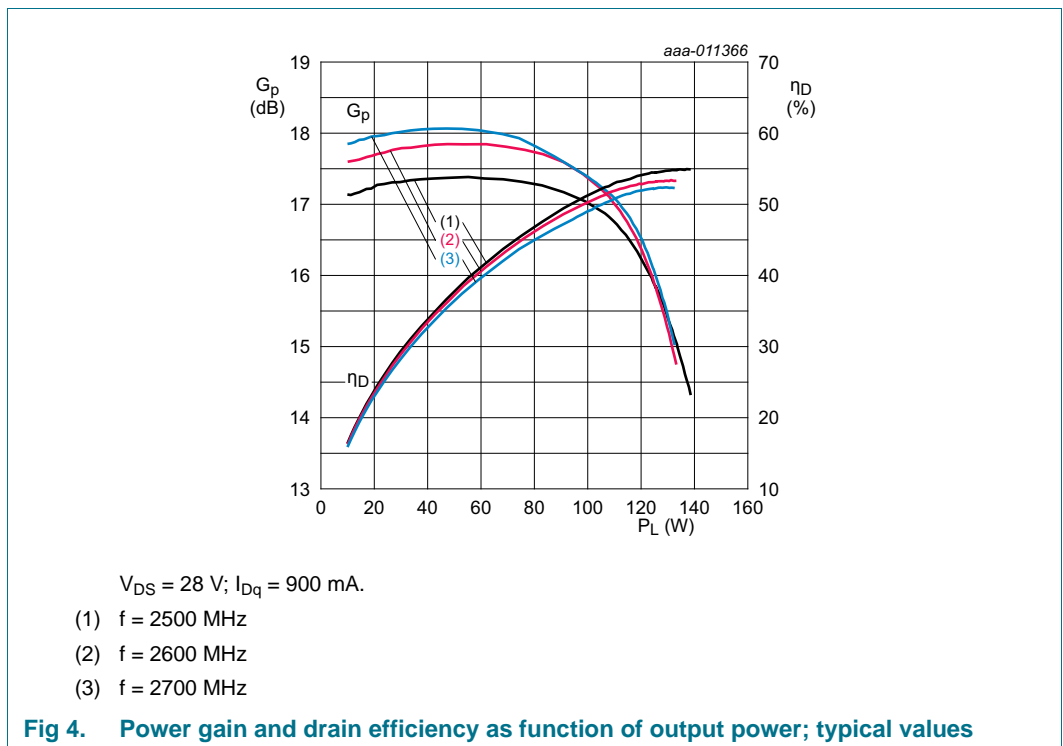
| Component | Description | Value | Remarks |
|------------------------------------|-----------------------------------|---------------|----------|
| C1, C2, C3, C6, C7, C10, C11, C12 | multilayer ceramic chip capacitor | 22 pF | ATC600F |
| C4, C5, C8, C9, C13, C14, C15, C16 | multilayer ceramic chip capacitor | 4.7 μF, 50 V | Murata |
| C17, C18 | electrolytic capacitor | 2200 μF; 50 V | |
| R1 | chip resistor | 9.1 Ω | SMD 0603 |
| X1 | copper foil strip | - | |

7.4 Graphical data

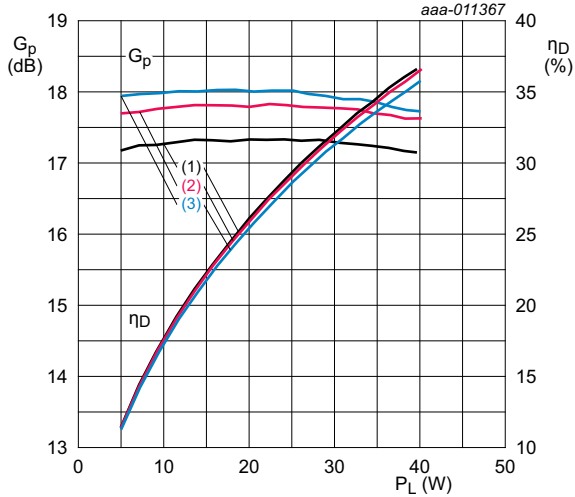
7.4.1 CW



7.4.2 CW pulsed

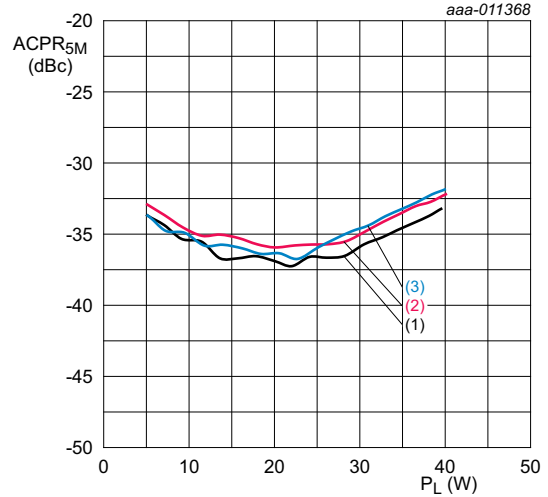


7.4.3 1-Carrier W-CDMA



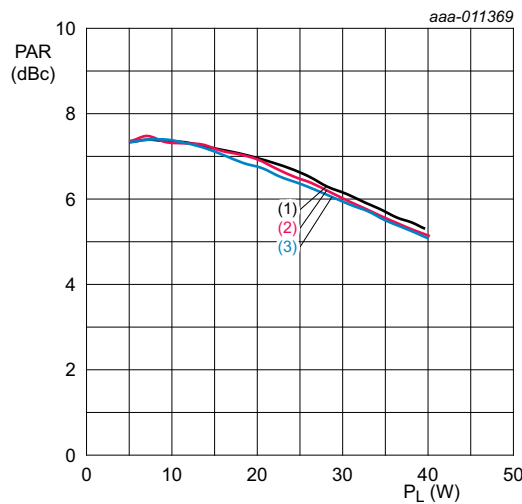
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

Fig 5. Power gain and drain efficiency as function of output power; typical values



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

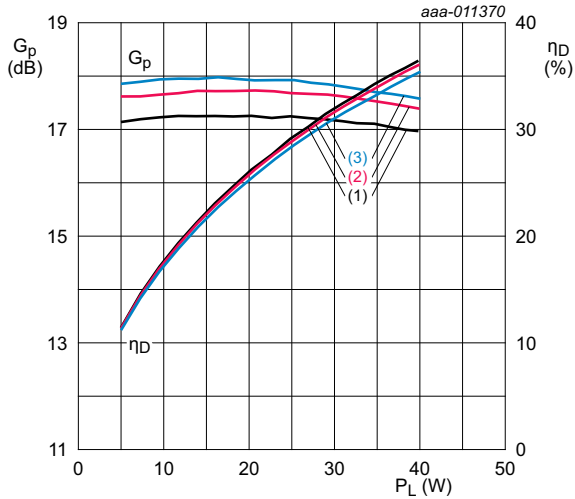
Fig 6. Adjacent power channel ratio (5 MHz) as a function of output power; typical values



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

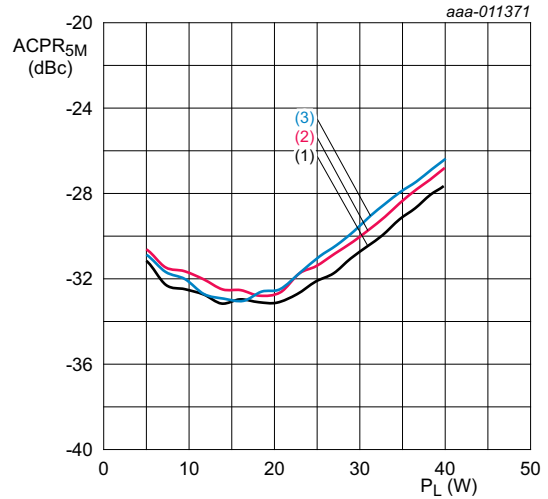
Fig 7. Peak-to-average ratio as a function of output power; typical values

7.4.4 2-Carrier W-CDMA



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

Fig 8. Power gain and drain efficiency as function of output power; typical values



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}.$
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

Fig 9. Adjacent power channel ratio (5 MHz) as a function of output power; typical values

8. Package outline

Earless flanged ceramic package; 2 leads

SOT502B

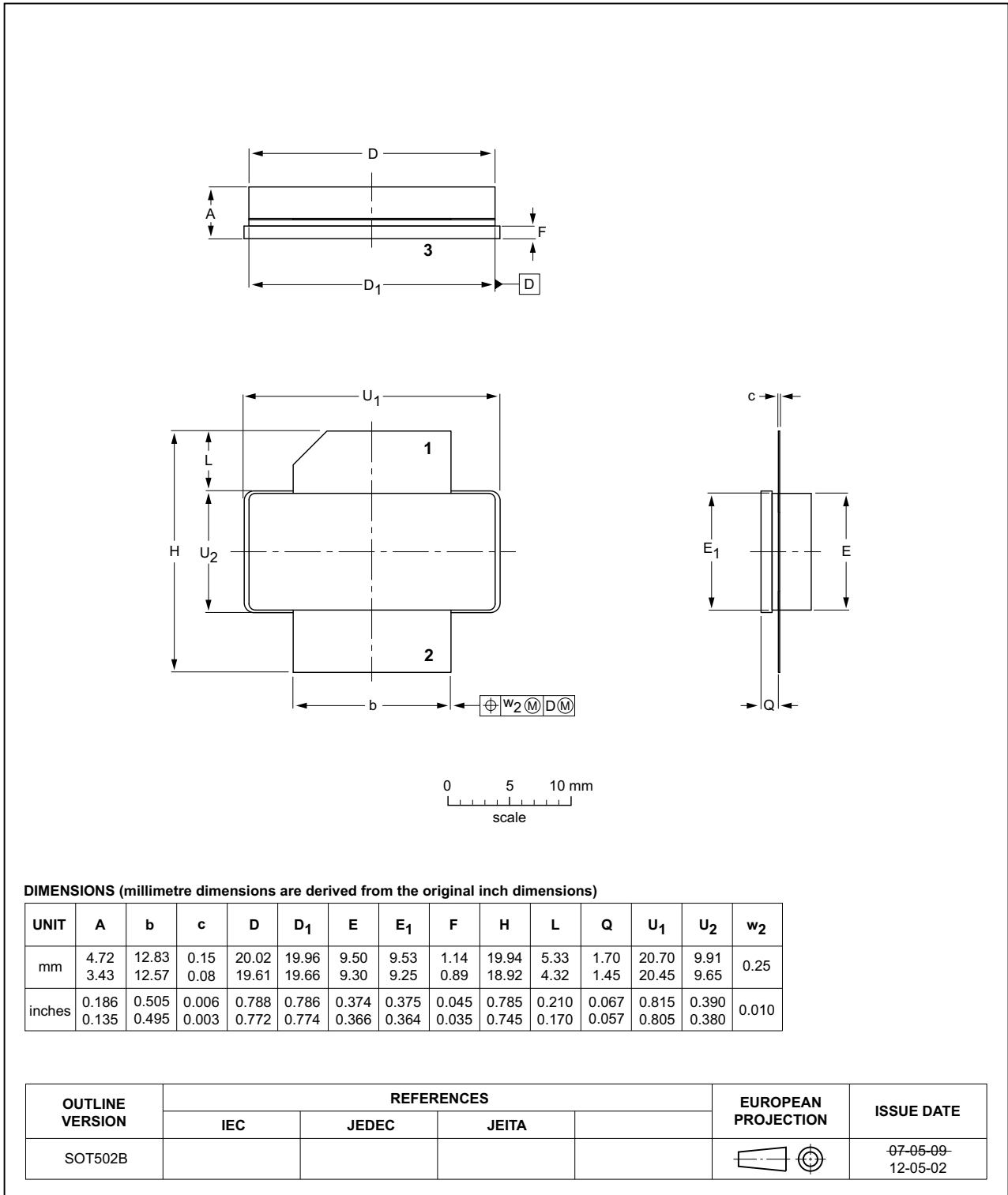


Fig 10. Package outline SOT502B

9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the *ANSI/ESD S20.20*, *IEC/ST 61340-5*, *JESD625-A* or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

| Acronym | Description |
|---------|--|
| 3GPP | 3rd Partnership Project |
| CCDF | Complementary Cumulative Distribution Function |
| CW | Continuous Wave |
| DPCH | Dedicated Physical CHannel |
| ESD | ElectroStatic Discharge |
| LDMOS | Laterally Diffused Metal Oxide Semiconductor |
| MTF | Median Time to Failure |
| PAR | Peak-to-Average Ratio |
| SMD | Surface Mounted Device |
| VSWR | Voltage Standing Wave Ratio |
| W-CDMA | Wideband Code Division Multiple Access |

11. Revision history

Table 11. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|-------------------|--|----------------------|---------------|-------------------|
| BLF8G27LS-100 v.2 | 20140305 | Product data sheet | - | BLF8G27LS-100 v.1 |
| Modifications | <ul style="list-style-type: none"> • Table 7 on page 3: table updated • Section 7 on page 3: section added | | | |
| BLF8G27LS-100 v.1 | 20131219 | Objective data sheet | - | - |

12. Legal information

12.1 Data sheet status

| Document status ^{[1][2]} | Product status ^[3] | Definition |
|-----------------------------------|-------------------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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